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RF EXPOSURE REPORT

REPORT NO.: SA131003D01

MODEL NO.: F5L155

FCC ID: K7SF5L155

RECEIVED: Oct. 3, 2013

TESTED: Oct. 3 ~ 9, 2013

ISSUED: Oct. 14, 2013

APPLICANT: Belkin International, Inc.

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ISSUED BY: Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch

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RELEASE CONTROL RECORD

ISSUE NO.	REASON FOR CHANGE	DATE ISSUED
SA131003D01	Original release.	Oct. 14, 2013



1. CERTIFICATION

PRODUCT: Thin Type Keyboard Case
BRAND: Belkin
MODEL NO.: F5L155
APPLICANT: Belkin International, Inc.
TESTED: Oct. 3 ~ 9, 2013
TEST SAMPLE: ENGINEERING SAMPLE
STANDARDS: **FCC Part 2 (Section 2.1093)**
FCC OET Bulletin 65, Supplement C (01-01)
IEEE C95.1

The above equipment has been tested by **Bureau Veritas Consumer Products Services (H.K.) Ltd., Taoyuan Branch**, and found compliance with the requirement of the above standards. The test record, data evaluation & Equipment Under Test (EUT) configurations represented herein are true and accurate accounts of the measurements of the sample's EMC characteristics under the conditions specified in this report.

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APPROVED BY : *Rex Lai* , **DATE:** Oct. 14, 2013
(Rex Lai / Assistant Manager)

2. EVALUATION RESULT

Following FCC KDB 447498 D01 “General SAR test exclusion guidance”

The corresponding SAR Exclusion Threshold condition, listed below:

1) The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, 16 where

- Ø $f(\text{GHz})$ is the RF channel transmit frequency in GHz.
- Ø Power and distance are rounded to the nearest mW and mm before calculation.
- Ø The result is rounded to one decimal place for comparison. The test exclusions are applicable only when the minimum test separation distance is ≤ 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

2) At 100 MHz to 6 GHz and for test separation distances > 50 mm, the SAR test exclusion threshold is determined according to the following:

- a) [Threshold at 50 mm in step 1) + (test separation distance - 50mm) · ($f(\text{MHz})/150$)] mW, at 100MHz to 1500 MHz
- b) [Threshold at 50 mm in step 1) + (test separation distance - 50 mm) · 10] mW at > 1500 MHz and ≤ 6 GHz

3) At frequencies below 100 MHz, the following may be considered for SAR test exclusion.

- a) The threshold at the corresponding test separation distance at 100 MHz in step 2) is multiplied by $[1 + \log(100/f(\text{MHz}))]$ for test separation distances > 50 mm and < 200 mm.
- b) The threshold determined by the equation in a) for 50 mm and 100 MHz is multiplied by $\frac{1}{2}$ for test separation distances ≤ 50 mm.
- c) SAR measurement procedures are not established below 100 MHz. When SAR test exclusion cannot be applied, a KDB inquiry is required to determine SAR evaluation requirements for any test results to be acceptable.

3. SAR TEST EXCLUSION THRESHOLDS

Maximum measured transmitter power:

Frequency (GHz)	Max. Power (mW)	Min. test separation distance (mm)	SAR test exclusion calculation value ^(NOTE 2)	1-g SAR test exclusion thresholds	Result
2.402 ~ 2.480	0.8	5	0.248	3	Pass

NOTE: 1. The antenna type is Chip antenna with -5.64dBi gain.

2. Calculate SAR test exclusion thresholds from condition "1" formulas.

4. CONCLUSION

Since Source-base time average power is below SAR test exclusion power thresholds, the SAR evaluation is not required.